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Application/Control No.	Applicant(s)/Patent under Reexamination
10/614,264	RODGERS ET AL.
Examiner	Art Unit
Chi Q. Nguyen	3635

SEARCHED			
Class	Subclass	Date	Examiner
52	742.14	6/30/2005	CN
	309.9		
	309.12		
	309.17		
	797.1		
	745.19		
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INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH N (INCLUDING SEAR		
	DATE EXM	ΙR
inventor's name search	6/30/2005 CN	١
search related art	6/30/2005 Cf	N
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